

FOR IMMEDIATE RELEASE

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AEHR TEST SYSTEMS APPOINTS LARRY ANDERSON AS VICE PRESIDENT OF WORLDWIDE SALES

Fremont, CA (May 29, 2012) - Aehr Test Systems (Nasdaq: AEHR), a worldwide supplier of semiconductor test and burn-in equipment, today announced that Larry Anderson has been appointed Vice President of Worldwide Sales. Mr. Anderson will direct Aehr Test's worldwide sales organizations.

Mr. Anderson has over 25 years of sales and sales management experience with technology companies including 10 years with FormFactor, a leader in the semiconductor test probe card market, where he headed the sales and service efforts in North America and Europe. Prior to joining Aehr Test, Mr. Anderson also held various sales leadership positions with the memory and logic test businesses of Advantest/Verigy, a leader in the semiconductor test business as well as Cymer, the leading laser light source company whose products are used for pattering advanced semiconductors. Mr. Anderson received a B.B.A. from Western Michigan University.

"We are pleased to have Larry join us. He brings strong experience in semiconductor test sales to Aehr Test," said Gayn Erickson, president and chief executive officer of Aehr Test Systems. "We are confident that his experience and industry relationships will help to further strengthen and expand our worldwide customer base. We believe that this is an excellent time to bring on board a person of Larry's caliber as we are seeing an upturn in activity for our FOXTM and ABTSTM families of sort test and burn-in products."

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS and FOX family of test and burn-in systems and the DiePak® carrier. The ABTS system is used in production and qualification testing of packaged parts for both low-power and high-power logic as well as all common types of memory devices. The FOX system is a full wafer contact test and burn-in system used for

burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of Aehr Test's technology, acceptance by customers of the systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K, 10-Q and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.